



UNIVERSITY OF ENERGY AND NATURAL RESOURCES, SUNYANI, GHANA
SCHOOL OF ENGINEERING

DEPARTMENT OF COMPUTER AND ELECTRICAL ENGINEERING

Level 200 End of First Semester Examinations 2020/2021

Bachelor of Science (Electrical & Electronic Engineering)

Bachelor of Science (Computer Engineering)

Bachelor of Science (Renewable Energy Engineering)

CENG 207: SOLID STATE ELECTRONIC DEVICES

April, 2021

Time: 2½ hours

Instructions: Attempt **Section A** on the question paper and **Section B** in the Answer Booklet

Material required: Class material / Hand-out (To be brought in by students- Useful data can be found on page 3)

Section A

1. In which quadrant of the junction I-V characteristics will a solar cell operate?
2. A 2V cell is applied across an n-type silicon sample of length 1cm. If the drift velocity of an electron in the sample is 3800 cm/s, calculate the diffusion coefficient of the sample.
3. What is the diffusion current density in a silicon sample whose hole density changes uniformly from $2 \times 10^{17} \text{cm}^{-3}$ to $1.2 \times 10^{11} \text{cm}^{-3}$ in a distance of $12 \mu\text{m}$?
4. A metal-insulator-semiconductor is realized using a metal of work function 4.85eV, SiO_2 as insulator and silicon doped with $3 \times 10^{18} \text{cm}^{-3}$ donor impurities as the semiconductor. Estimate the flat band voltage VFB.
5. A holes in a Si sample undergoes collision for an average time of 2.5p.s. If the hole is subject to a field of $E = 10^3 \text{ V/cm}$ and has a mobility of $4.70 \text{ cm}^2/\text{V.s}$. Find the distance travelled.
5. A Si sample is doped with 2×10^{17} Arsenic atoms/ cm^3 . Calculate the equilibrium hole concentration p_0 at 300K

191

7. Find the resistivity of intrinsic Silicon at 300K [$\mu_n=1250 \text{ cm}^2/\text{Vs}$; $\mu_p=480 \text{ cm}^2/\text{Vs}$]

8. The same Si sample (question 6) is further doped with $7 \times 10^{15} \text{ cm}^{-3}$ acceptors. What type of extrinsic material?

9. An npn transistor is biased in the forward active mode. The base current $I_B=9.6 \mu\text{A}$ and the emitter current $I_E=0.780 \text{ mA}$. Find β and the collector current I_C

10. Name any two types of PNP devices.

Section B: Answer in the Answer BOOKLET

Question 1 [5 x 2 = 10]

A $10 \text{ k}\Omega$ resistor is to be designed to handle a current density of 50 A/cm^2 when a 5V is applied. If this resistor is limited to electric field of $E=100 \text{ V/cm}$ and is made of p-type Silicon material with $\mu=410 \text{ cm}^2/\text{V-s}$, calculate:

- current passing through the resistor
- cross-sectional area
- length of the resistor
- conductivity
- concentration

Question 2 [2 x 10 = 20]

(a) Consider a uniformly doped silicon bipolar transistor at $T=300\text{K}$ with a base doping of $N_B=5 \times 10^{16} \text{ cm}^{-3}$ and collector doping of $N_C=2 \times 10^{15} \text{ cm}^{-3}$. Assume the metallurgical base width is $0.70 \mu\text{m}$. Calculate the percentage change in neutral base width as the C-B voltage changes from 2 to 10 V.

(b) The electron concentration in silicon is given by $n(x) = 10^{15} e^{-(x/L_n)} \text{ cm}^{-3}$ ($x \geq 0$), where $L_n = 10^{-4} \text{ cm}$. The electron diffusion coefficient is $D_n = 25 \text{ cm}^2/\text{s}$. Determine the electron diffusion current density at $x = 0$.

Question 3 [2 x 5 = 10]

- Distinguish between an Enhancement and Depletion MOSFETs with diagrams
- State the difference between a PN junction diode and a Schottky diode
- What is a degenerative semiconductor?
- Distinguish between a Bipolar transistor and Junction Field Effect transistor with diagrams.
- Using the I-V characteristics of a p-n junction under various levels illumination, explain the photoconductive and photovoltaic effects.

PHYSICAL CONSTANTS

q	Electronic Charge	1.602×10^{-19}	C		
ϵ_0	Permittivity of Free Space	8.854×10^{-14}	F.cm ⁻¹		
μ_0	Permeability of Free Space	1.2566×10^{-8}	H.cm ⁻¹		
k	Boltzmann Constant	1.38×10^{-23}	J.K ⁻¹	8.62×10^{-5}	eV.K ⁻¹
h	Planck Constant	6.626×10^{-34}	J.s		
m_0	Electron Rest Mass	9.11×10^{-31}	kg		
eV	Electron Volt	1.602×10^{-19}	J		
c	Speed of Light	3×10^8	m.s ⁻¹		
kT/q	Thermal Voltage (300K)	0.025	V		

SOME PROPERTIES OF SILICON

n_i	Intrinsic Carrier Concentration	1.5×10^{10}	cm ⁻³
N_c	Effective Density of States (CB)	2.8×10^{19}	cm ⁻³
N_v	Effective Density of States (VB)	1.04×10^{19}	cm ⁻³
E_g	Band Gap	1.12	eV
ϵ_s	Dielectric Constant	11.8	
ϵ_{ox}	Dielectric Constant	3.6	
χ	Electron affinity (Si)	4.05	V